

Quantitative Evaluation Methods

◆ Random Variable X

- a function that assigns a real number $X(s)$ to each sample point s in sample space S
- e.g. coin toss, number of heads in a sequence of 3 tosses

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s	hhh	hht	hth	htt	thh	tht	tth	ttt
$X(s)$	3	2	2	1	2	1	1	0

- X is a random variable taking on values in the set

$$S_X = \{0,1,2,3\}$$

Quantitative Evaluation Methods

◆ Cumulative Distribution Function (cdf)

- The cdf of a random variable X is defined as the probability of the event

$$\{X \leq x\}$$

$$F_X(x) = P(X \leq x) \text{ for } -\infty < x < +\infty$$

$$F_X(x) = \text{prob. of event } \{s: X(s) \leq x\}$$

$$F_X(x) = \text{is a probability, i.e. } 0 \leq F_X(x) \leq 1$$

$$F_X(x) \text{ is monotonically non-decreasing,}$$

$$\text{i.e. if } x_1 \leq x_2 \text{ then } F_X(x_1) \leq F_X(x_2)$$

$$\lim_{x \rightarrow \infty} F_X(x) = 1$$

$$\lim_{x \rightarrow -\infty} F_X(x) = 0$$

Quantitative Evaluation Methods

- ◆ Probability Density Function (pdf)
 - The pdf of a random variable is the derivation of $F_X(x)$

$$f_X(x) = \frac{dF_X(x)}{dx}$$

- Since $F_X(x)$ is a non-decreasing function,

$$f_X(x) \geq 0$$

Quantitative Evaluation Methods

- ◆ Expectation of a random variable
 - in order to completely describe the behavior of a random variable, an entire function, namely the cdf or pdf, must be given
 - however, sometime we are just interested in parameters that summarize information

$$E(X) = \int_{-\infty}^{\infty} x f_X(x) dx$$

i.e. mean time to failure = expected lifetime of the system

Reliability $R(t)$

- ◆ $R(t)$ = probability that system is working at time t , and any time before that $\Rightarrow [0,t]$
- ◆ X = random variable representing life of system
- ◆ Let

N = initial number of resources of a system

$N_o(t)$ = number of resources operating at time t

$N_f(t)$ = number of resources failed at time t

Reliability $R(t)$

$$\begin{aligned}R(t) &= P(X > t) \\ &= 1 - P(X \leq t) \\ &= 1 - Q(t) \\ &= 1 - \frac{N_f(t)}{N}\end{aligned}$$

$$\frac{dR(t)}{dt} = -\frac{1}{N} \frac{dN_f(t)}{dt}$$

$$\frac{dN_f(t)}{dt} = -N \frac{dR(t)}{dt}$$

instantaneous rate at which components are failing

$$\frac{dN_f(t)}{dt} = -N \frac{dR(t)}{dt} \quad (1)$$

div by $N_o(t)$
to get

$$z(t) = \frac{1}{N_o(t)} \frac{dN_f(t)}{dt} \quad (2)$$

this is called

hazard function

hazard rate

failure rate function

which is the normalized failure rate

using (1) in (2), i.e.

$$\frac{dN_f(t)}{dt} = -N \frac{dR(t)}{dt}$$

$$z(t) = \frac{1}{N_o(t)} \frac{dN_f(t)}{dt}$$

we get

$$z(t) = - \frac{N}{N_o(t)} \frac{dR(t)}{dt}$$

expressed in terms of Reliability only with $R(t) = \frac{N_o(t)}{N}$

$$z(t) = - \frac{1}{R(t)} \frac{dR(t)}{dt}$$

expressed in term of unreliability $Q(t)$

$$\begin{aligned}z(t) &= -\frac{1}{R(t)} \frac{dR(t)}{dt} \\ &= -\frac{1}{1-Q(t)} \frac{d(1-Q(t))}{dt} \\ &= \frac{1}{1-Q(t)} \frac{dQ(t)}{dt}\end{aligned}$$

Result often used:

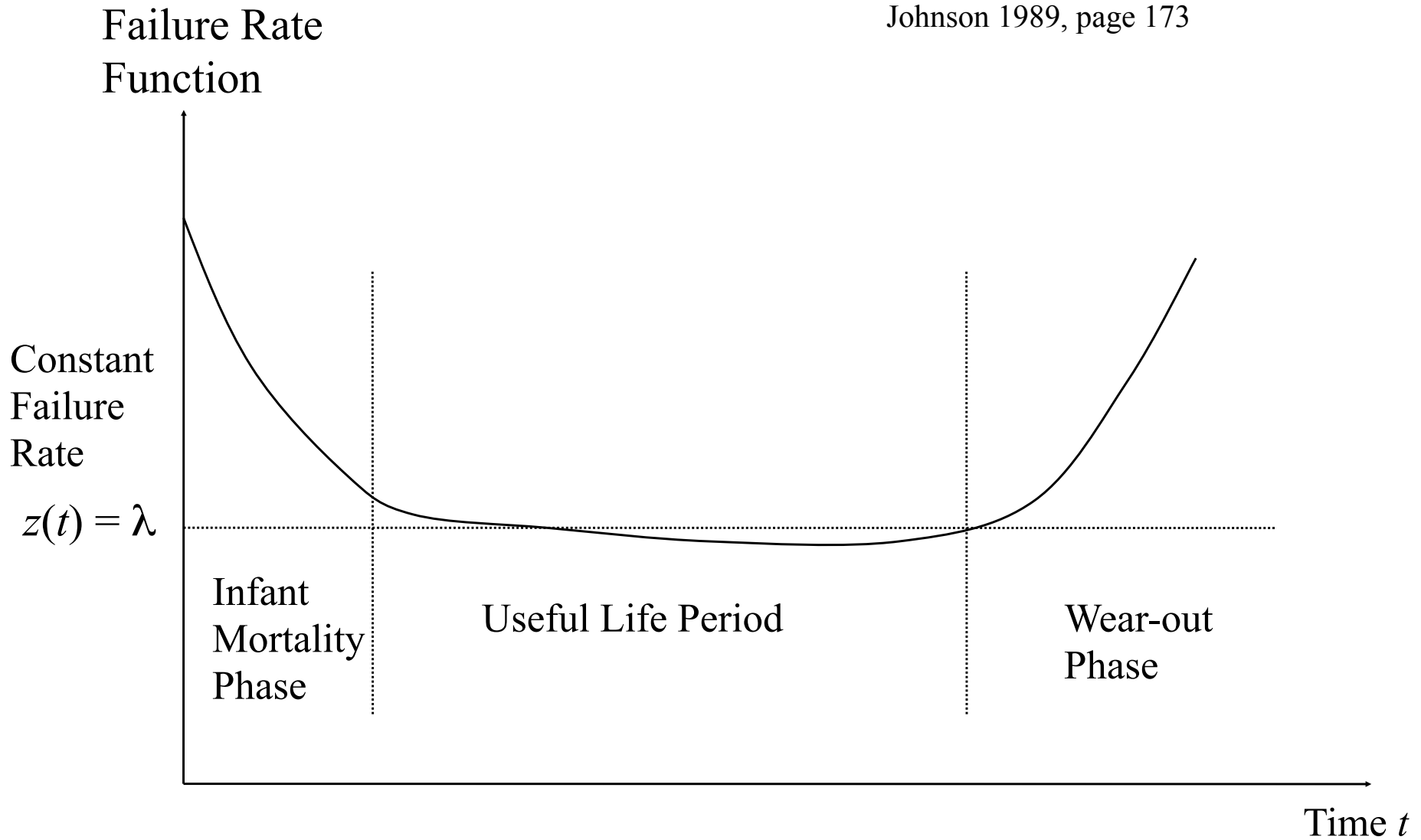
$$\frac{dR(t)}{dt} = -z(t)R(t)$$

Bathtub Curve

- ◆ Infant mortality phase
 - burn-in to bypass infant mortality
- ◆ Useful life period
- ◆ Wear-out phase
 - exchange before wear-out phase
- ◆ Therefore one may assume constant failure rate function $z(t)$, i.e. $z(t) = \lambda$

Bathtub Curve

Johnson 1989, page 173



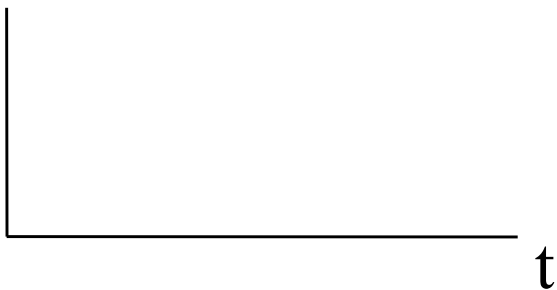
assuming constant $z(t)$

$$\begin{aligned}\frac{dR(t)}{dt} &= -z(t)R(t) \\ &= -\lambda R(t)\end{aligned}$$

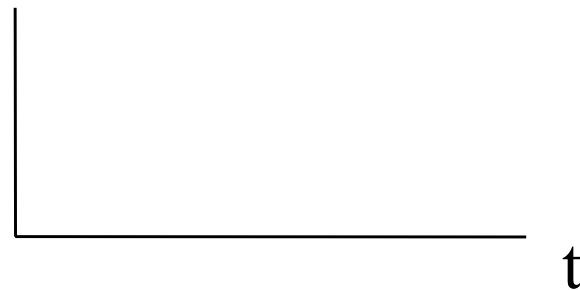
solving the differential equation we get

$$R(t) = e^{-\lambda t}$$

R(t)



Q(t)



solving $\frac{dR(t)}{dt} = -\lambda R(t)$

$$\frac{R'(t)}{R(t)} = -\lambda$$

$$\int \lambda dt = -\int_0^t \frac{R'(t)}{R(t)} dt$$

$$= -\int_{R(0)}^{R(t)} \frac{dR}{R}$$

$$-\ln R(t) = \int_0^t \lambda dt$$

$$R(t) = e^{-\lambda t}$$

Mean Time to Failure (MTTF)

Expected lifetime

$$E[X] = \int_{-\infty}^{\infty} xf(x)dx$$

Mean Time to Failure

$$MTTF = \int_{-\infty}^{\infty} tf(t)dt$$

where $f(t)$ is the failure density function

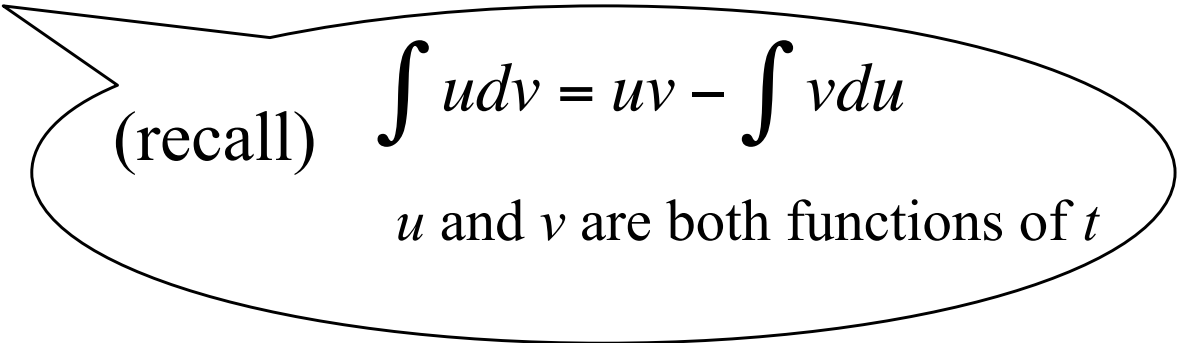
$$f(t) = \frac{dQ(t)}{dt} = \frac{d(1 - R(t))}{dt}$$

Mean Time to Failure (MTTF)

Now, we can rewrite

$$\frac{d(1 - R(t))}{dt} = -\frac{dR(t)}{dt}$$

and use integration by parts



(recall) $\int u dv = uv - \int v du$

u and v are both functions of t

to get

$$MTTF = \int_0^{\infty} t \frac{Q(t)}{dt} dt = -\int_0^{\infty} t \frac{R(t)}{dt} dt = \left[-tR(t) + \int R(t) dt \right]_0^{\infty} = \int_0^{\infty} R(t) dt$$

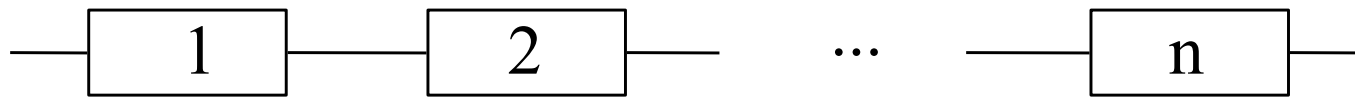
Mean Time to Failure (MTTF)

Thus the expected lifetime is

$$\begin{aligned} E(t) &= \int_0^{\infty} R(t) dt \\ &= \int_0^{\infty} e^{-\lambda t} dt \\ &= \frac{1}{-\lambda} e^{-\lambda t} \Big|_0^{\infty} \\ &= \frac{1}{\lambda} \end{aligned}$$

Reliability of Series System

- ◆ Any one component failure causes system failure
- ◆ Reliability Block Diagram (RBD)



$$R(t)_{\text{series}} = \prod_{i=1}^n R_i(t)$$

$$= \prod_{i=1}^n e^{-\lambda_i t}$$

$$= e^{-\left(\sum_{i=1}^n \lambda_i\right)t}$$

Reliability of Series System

thus
$$\lambda_{\text{series}} = \sum_{i=1}^n \lambda_i$$

Mean time to failure of series system:

$$MTTF_{\text{series}} = \frac{1}{\sum_{i=1}^n \lambda_i}$$

Thus the MTTF of the series system is much smaller than the MTTF of its components

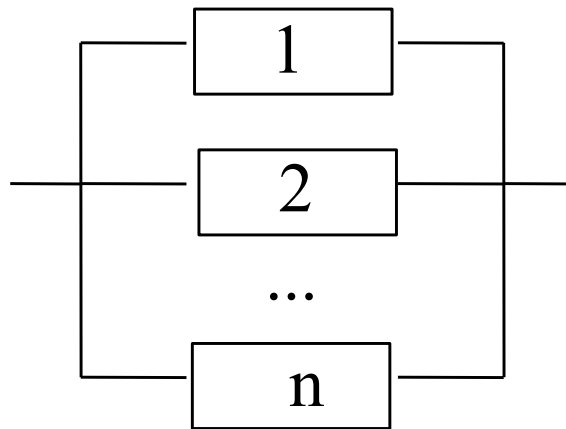
if $X_i \equiv$ lifetime of component i then

$$0 \leq E[X] \leq \min\{E[X_i]\}$$

system is weaker
than weakest
component

Reliability of Parallel System

- ◆ All components must fail to cause system failure
- ◆ Reliability Block Diagram (RBD)



- assume mutual independence

X is lifetime of the system

$$X = \max \{X_1, X_2, \dots, X_n\} \quad \text{n components}$$

$$\begin{aligned} R(t)_{\text{parallel}} &= 1 - \prod_{i=1}^n Q_i(t) \\ &= 1 - \prod_{i=1}^n (1 - R_i(t)) \\ &\geq 1 - (1 - R_i(t)) \end{aligned}$$

Assuming all components have exponential distribution with parameter λ

$$R(t) = 1 - (1 - e^{-\lambda t})^n$$

$$\begin{aligned}
E(X) &= \int_0^{\infty} [1 - (1 - e^{-\lambda t})^n] dt \\
&= \dots \\
&= \frac{1}{\lambda} \sum_{i=1}^n \frac{1}{i} \\
&\approx \frac{\ln(n)}{\lambda}
\end{aligned}$$

Trivedi 1982, Page 218

from previous page

$$Q(t)_{\text{parallel}} = \prod_{i=1}^n Q_i(t)$$

Product law of
unreliability